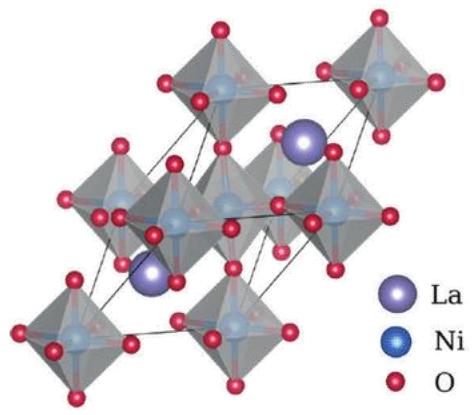




# Relationship Processing-Composition- Structure-Resistivity of $\text{LaNiO}_3$ Thin Films Grown by Chemical Vapor Deposition Methods

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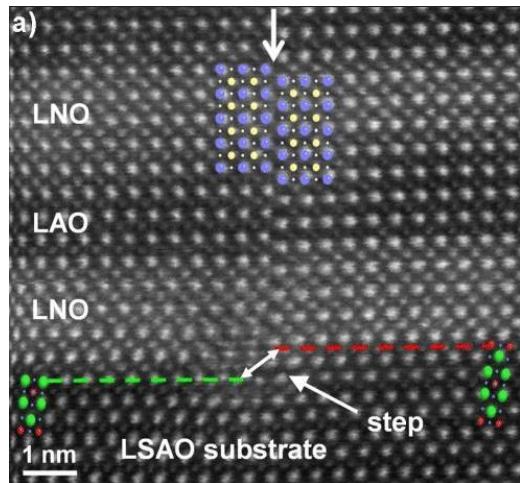


$\text{LaNiO}_3$  crystal structure

- **$\text{LaNiO}_3$  : seed layer and bottom electrode**
- **Processes presentations (chemicals and reactor parameters)**
- **Stoichiometry and resistivity**
- **Epitaxial relationship and crystallographic orientation**
- **Conclusion**

# $\text{LaNiO}_3$ : Seed layer and bottom electrode

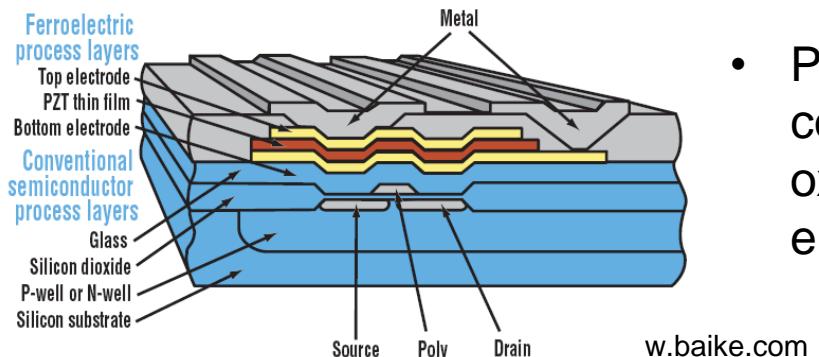
## LNO-LAO superlattices (SLs)



- Intriguing phenomenon at the interface unattainable in bulk

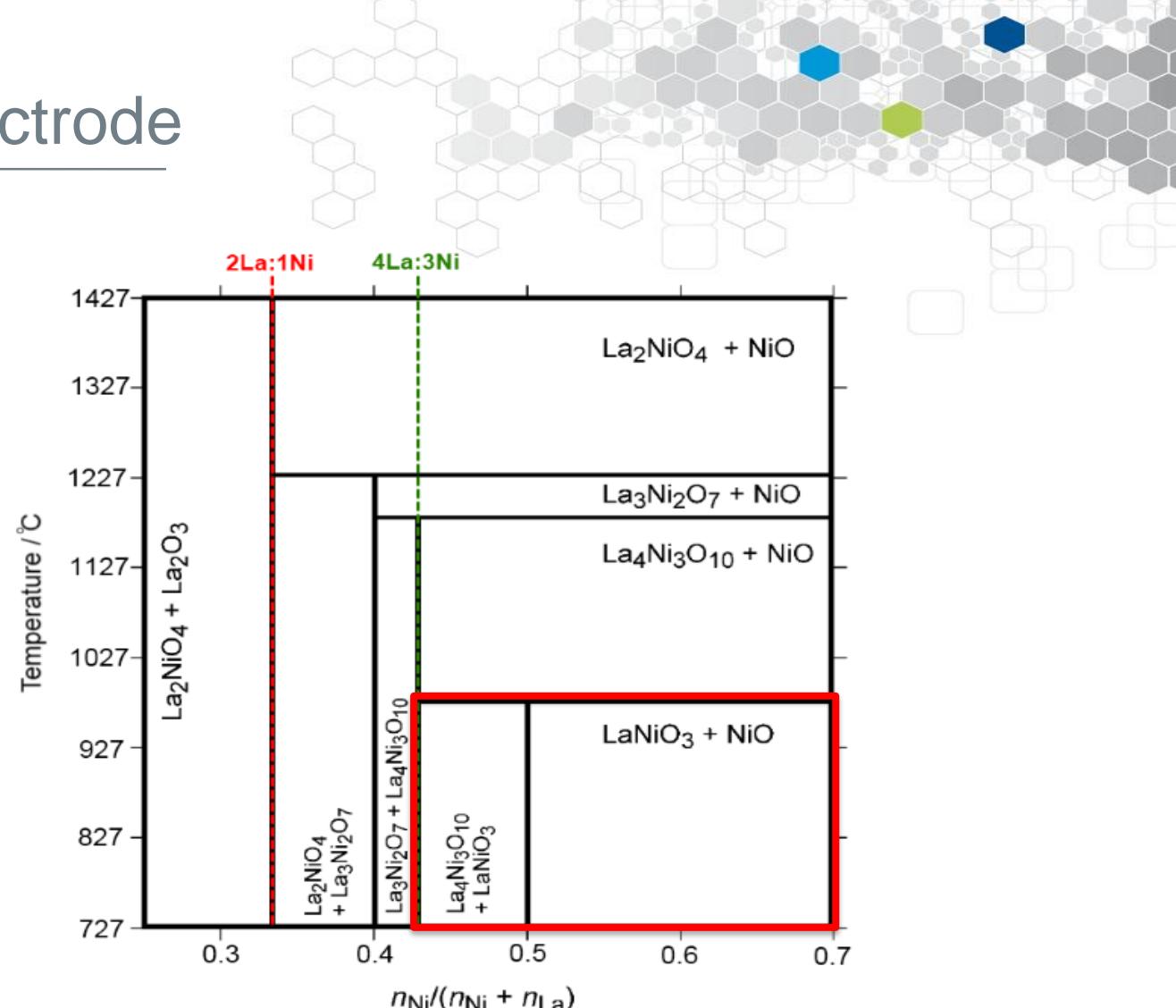
Detemple, E. et al. *Microscopy and Microanalysis* 19.S2 (2013): 1888-1889.

## $\text{Pb}(\text{Zr},\text{Ti})\text{O}_3$ Ferroelectric RAM



- Perovskite conducting oxide as an electrode

wbaike.com



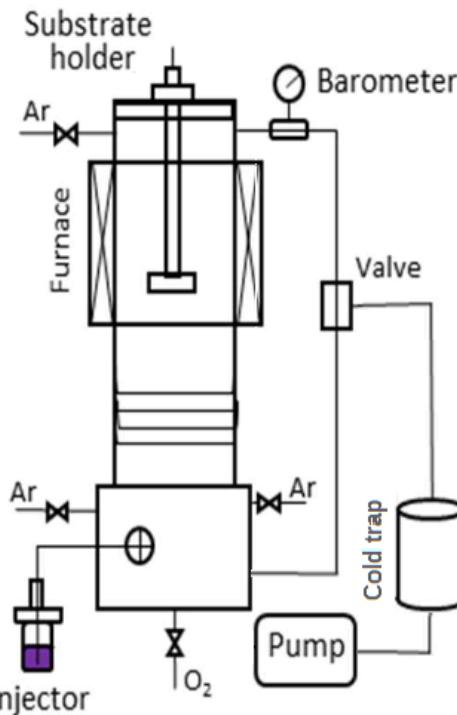
$\text{La}_2\text{O}_3 - \text{NiO}$  phase diagram

Woolley, R. J., et al. *Journal of Power Sources* 243 (2013): 790-795.

# Apparatus

→ Three different MOCVD methods : PI-MOCVD, DLI-MOCVD and AP-MOCVD

## Pulsed Injection-MOCVD

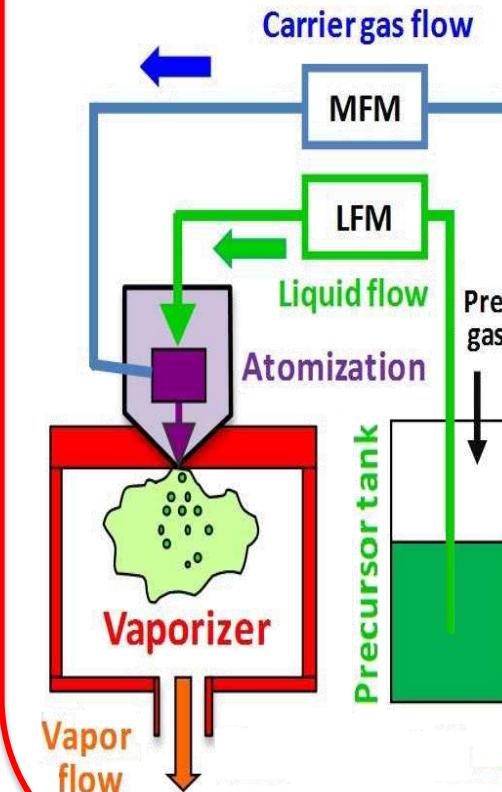


boschautoparts.com

Solvent:  
1,2-dimethoxyethane  
(monoglyme)

Characteristic:  
Atomization and  
fast vaporization of  
a liquid precursor.

## Direct Liquid Injection-MOCVD



kemstream.com

Solvent (+ Lewis Base):  
Toluene (+ monoglyme)  
Monoglyme  
Mesitylene (+ TMEDA)

Characteristic:  
Atomization and fast  
vaporization of a mixture of  
gas and liquid precursor.

# Chemical Vapor Deposition study

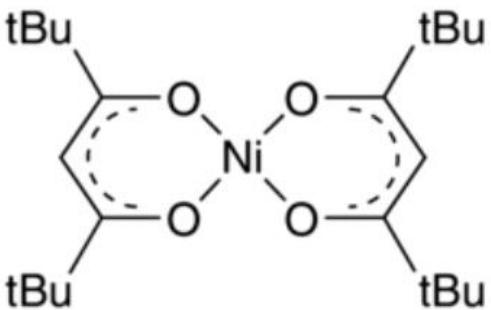


## Liquid

- Adding a Lewis Base (monoglyme, TMEDA etc.) helps to control the coordination sphere of the metallic center and/or its oxidation state.
  - Limit aggregation and oligomerization of the precursor to enhance vaporization

## CVD parameters mapping

- Set precursors :  $\beta$ -diketonates – La(thd)<sub>3</sub> and Ni(thd)<sub>2</sub>
- Ratio of La(thd)<sub>3</sub> to Ni(thd)<sub>2</sub> in solution : 1 – 2,2
- Evaporation temperature : 150 – 300 °C
- Deposition temperature : 425 – 750 °C
- Pressure : 2 – 15 Torr



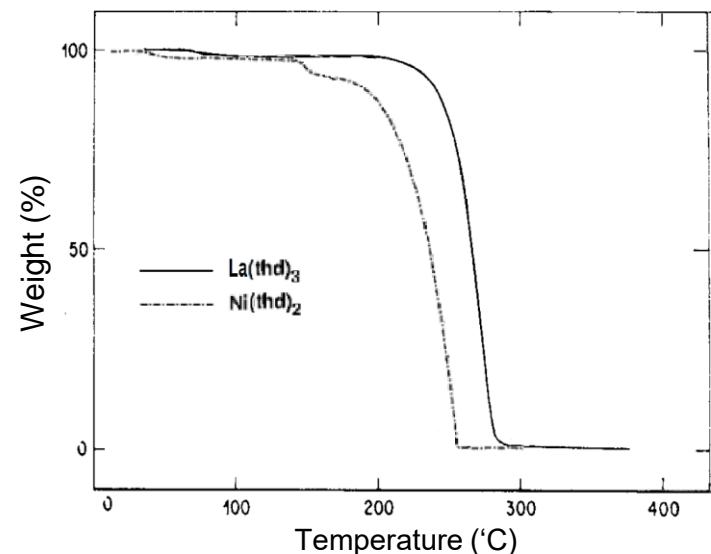
Solid is purple

## Film properties

- Stoichiometry
- Resistivity
- Crystallographic orientation

Turns green in coordinating solvents. Otherwise remains purple.

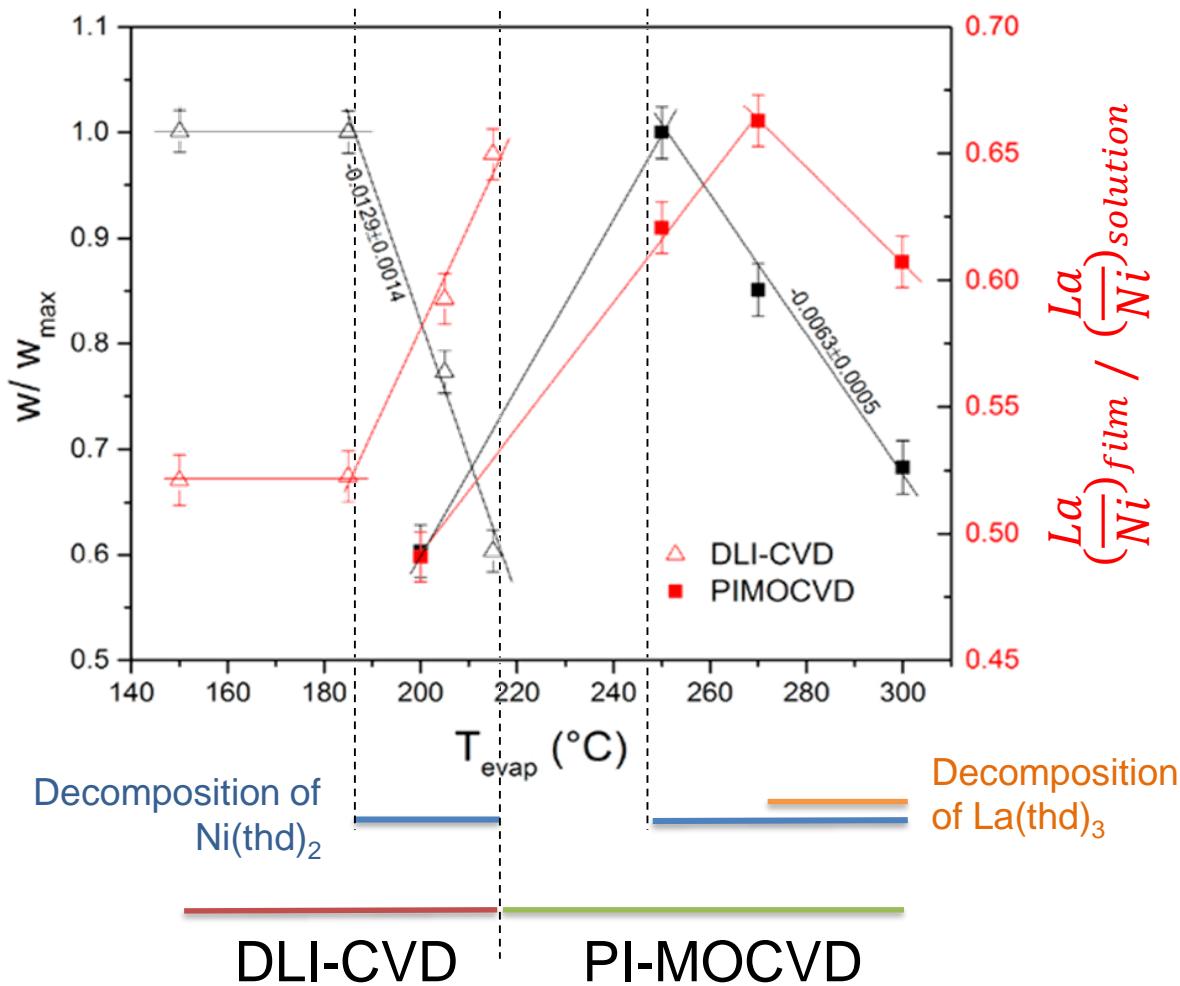
# Evaporation conditions



- $\text{La}(\text{thd})_3$  is less volatile than  $\text{Ni}(\text{thd})_2$
- Residues negligible
- Temperature can be brought down in vacuum conditions

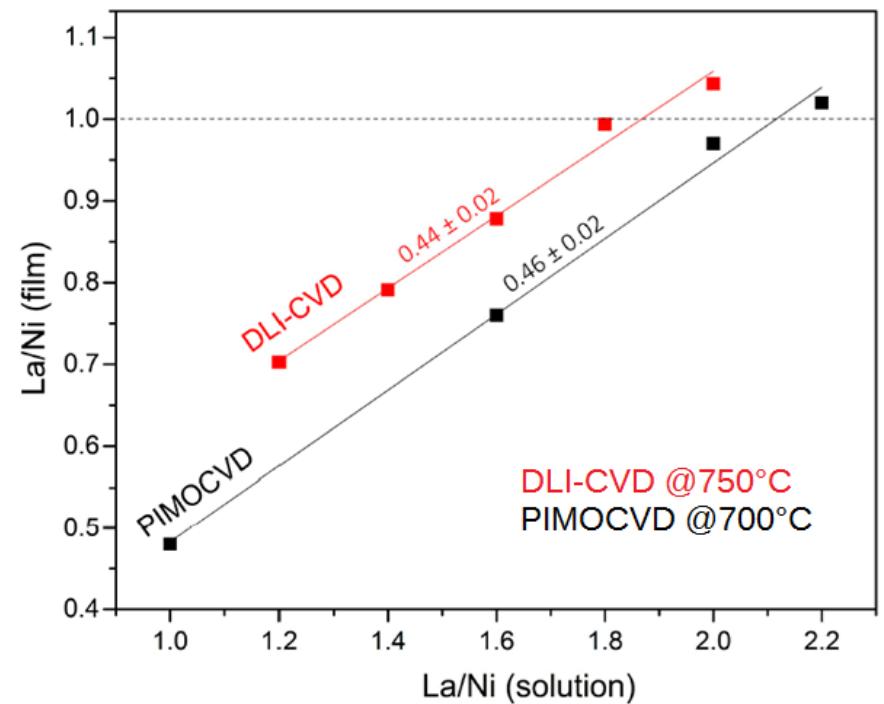
Eisentraut, K. *Journal of Inorganic and Nuclear Chemistry* 29.8 (1967): 1931-1936.  
Jones, A.C. *Chemical Vapor Deposition*, 1998.  
4(5): p. 169-179.

Normalized growth rate and molar ratio between  $\text{La}/\text{Ni}$  in the film and in the solution as a function of evaporation temperature



# Solution and film stoichiometry

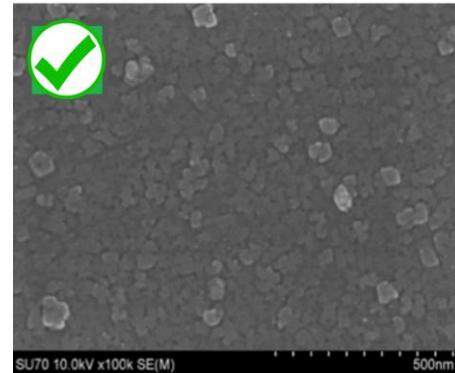
Relationship between La/Ni molar ratios in the LNO film and in the solution of precursors at deposition temperatures of 750 °C and 700 °C in DLI-CVD and PIMOCVD, respectively;



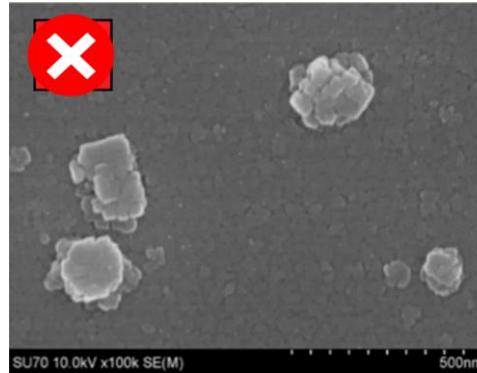
Both vacuum methods show a similar slope !

$$(\frac{La}{Ni})_{film} \approx 0,45 * (\frac{La}{Ni})_{injection}$$

- Hillocks formation on the surface when above 50%  $\text{La}_2\text{O}_3$



Nearly stoichiometric



$\text{La}_2\text{O}_3$ -rich

- $\text{La}_2\text{O}_3$  is unstable in air and thus AP-MOCVD showed lanthanum hydroxide or carbonate

# Crystallographic orientation

Note: LNO, Rhombohedral,  $R-3c$  ( $a = 5,454 \text{ \AA}$  and  $c = 13,106 \text{ \AA}$ )

Substrates considered :

- **Strontium Titanate  $\text{SrTiO}_3$**  : Cubic,  $Pm-3m$  ( $a = 3,905 \text{ \AA}$ )
- **Lanthanum Aluminate  $\text{LaAlO}_3$**  : Rhombohedral,  $R-3c$  ( $a = 5,365 \text{ \AA}$  and  $c = 13,112 \text{ \AA}$ )
- **Corundum  $\text{Al}_2\text{O}_3$**  : Rhombohedral,  $R-3c$  ( $a = 4,758 \text{ \AA}$  and  $c = 12,993 \text{ \AA}$ )

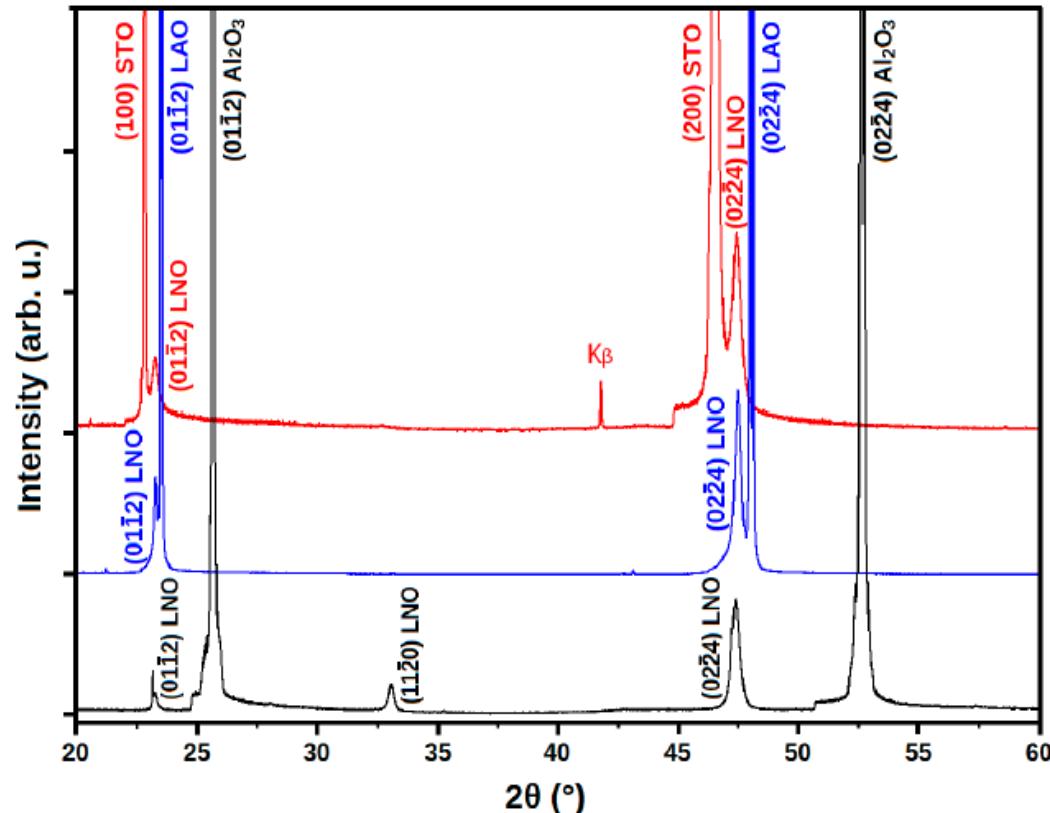
## Lattice mismatch

$(01\bar{1}2)_{LNO} \parallel (100)_{STO}$   
mismatch : <3%

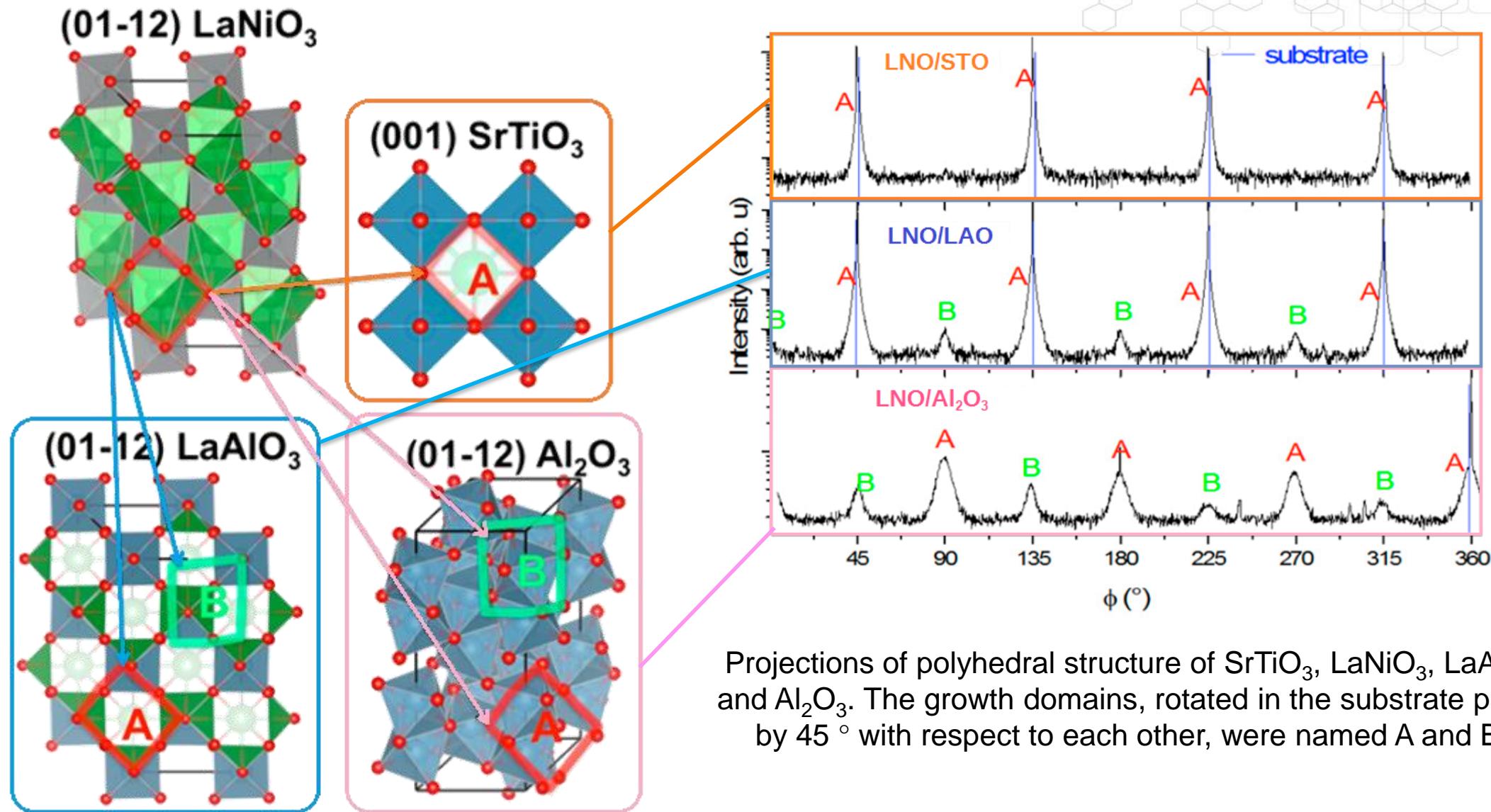
$(01\bar{1}2)_{LNO} \parallel (01\bar{1}2)_{LAO}$   
mismatch : <2%

$(01\bar{1}2)_{LNO} \parallel (01\bar{1}2)_{Al_2O_3}$   
mismatch : <13%

$(11\bar{2}0)_{LNO} \parallel (01\bar{1}2)_{Al_2O_3}$   
mismatch : <3%



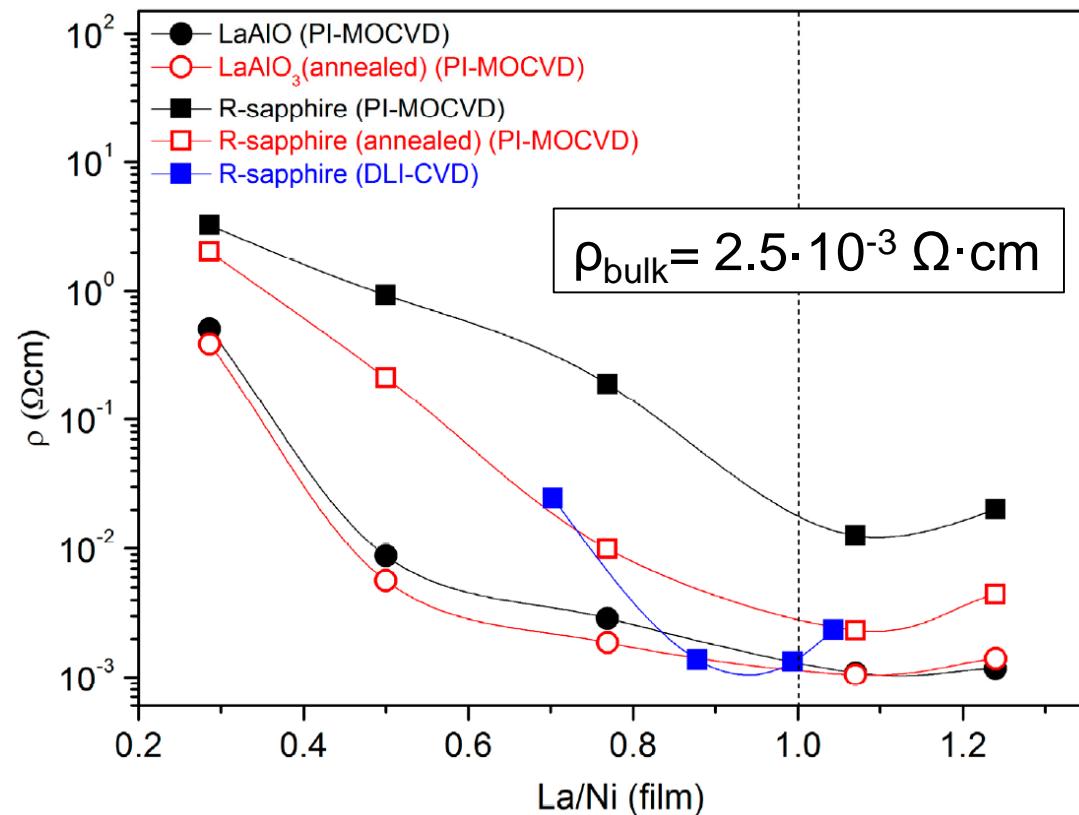
# Crystallographic orientation



# Resistivity



**Key parameter : Stoichiometry in oxygen, structural defects and  $\text{La}_2\text{O}_3$ -NiO ratio**



Composition dependence of resistivity of as-deposited and annealed  $\text{LaNiO}_3$  films on  $\text{LaAlO}_3$  and R-sapphire substrates.

- **Annealing at 750 °C in air significantly reduced resistivity in LNO/ $\text{Al}_2\text{O}_3$  structures (down to  $2.3 \cdot 10^{-3} \Omega \cdot \text{cm}$ )**
  - Recrystallization
- **$1.26 \cdot 10^{-3} \Omega \cdot \text{cm}$  by direct growth on  $\text{Al}_2\text{O}_3$  at 750 °C !**
- **$\text{La}_2\text{O}_3$ -NiO stoichiometry also impacts resistivity**

$$\rho_{(\text{LNO}/\text{Al}_2\text{O}_3)} = 1.26 \cdot 10^{-3} \Omega \cdot \text{cm}$$
$$\rho_{(\text{LNO}/\text{LAO})} = 1.05 \cdot 10^{-3} \Omega \cdot \text{cm}$$

# Conclusion

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- Fine control of the deposition parameters allows fine tuning of the  $\text{LaNiO}_3$  layer properties
- $\text{LaNiO}_3$  was epitaxially grown by MOCVD on  $\text{SrTiO}_3$ ,  $\text{LaAlO}_3$  and  $\text{Al}_2\text{O}_3$  at 650-750°C, and X-Ray diffraction showed that 2 families of growth domains coexisted in the two later substrates
- Nearly stoichiometric composition and annealing in air drastically reduces resistivity in LNO layers though reduction of micro defects
- Resistivity as low as  $1.05 \cdot 10^{-3} \Omega \cdot \text{cm}$  were obtained on high quality epitaxial LNO/LAO structures and  $1.26 \cdot 10^{-3} \Omega \cdot \text{cm}$  on LNO/ $\text{Al}_2\text{O}_3$  (bulk  $\sim 2.5 \cdot 10^{-3} \Omega \cdot \text{cm}$ ) without any post-annealing

# Acknowledgments

## FEMTO-ST Institute:

G. Clementi, S. Oliveri, S. Kuprenaite,  
A. Almirall, V. Astié, A. Borzi, A.  
Cavallaro

## Colleagues:

C. Millon

## University of Lorraine:

S. Margueron, P. Boulet

## University of Vilnius:

Z. Saltyte, V. Plausinaitiene, A. Abrutis

## Annealsys:

J.M. Decams, F. Laporte

## Kemstream:

H. Guillon





Thank you for your attention



Any questions ?



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